

Supplementary Material

Two Dimensional HfS₂-ZrS₂ Lateral Heterojunction FETs with High Rectification and Photocurrent

Lin Li,^{a,b} Peize Yuan,^c Zinan Ma,^a Mengjie He,^a Yurong Jiang,^a Tianxing Wang,^a

Congxin Xia,^a Xueping Li^{a,c,*}

^a School of physics, Henan Key Laboratory of Infrared Materials & Spectrum Measures and Applications, Henan Normal University, Xinxiang, Henan 453007, China.

^b College of Physics and Optoelectronic Engineering, Zhengzhou Key Laboratory of Low-dimensional Quantum Materials and Devices, Zhongyuan University of Technology, Zhengzhou, 450007, China.

^c College of Electronic and Electrical Engineering, Henan Normal University, Xinxiang, Henan 453007, China

* E-mail: lxpslxhww@126.com

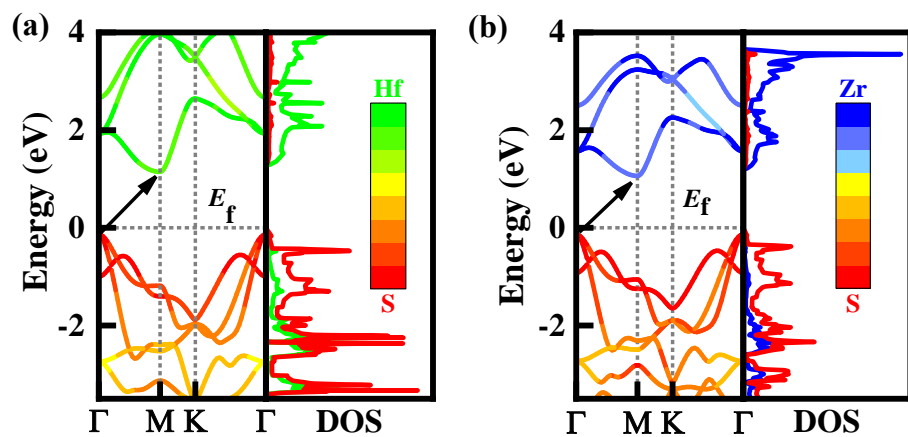


Fig. S1. The projected band structures for monolayer (a) HfS₂ and (b) ZrS₂.

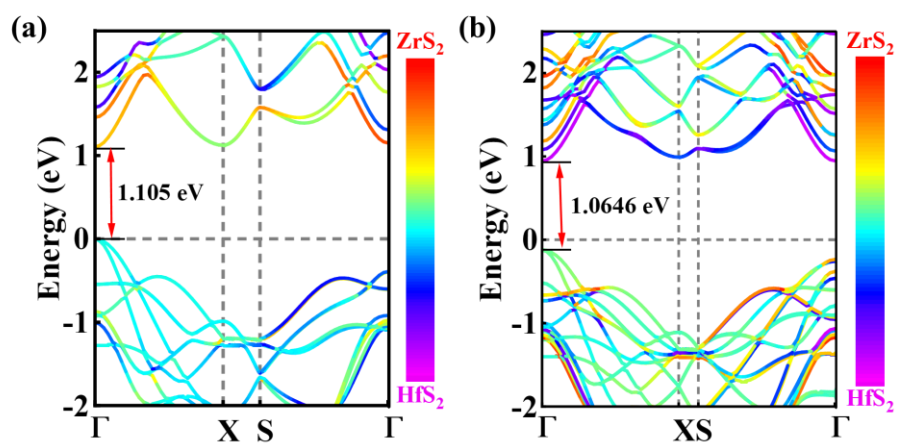


Fig. S2. The projected band structures for monolayer (a) $(\text{HfS}_2)_1\text{-(ZrS}_2)_1$ and (b) $(\text{HfS}_2)_2\text{-(ZrS}_2)_2$ lateral heterojunction.

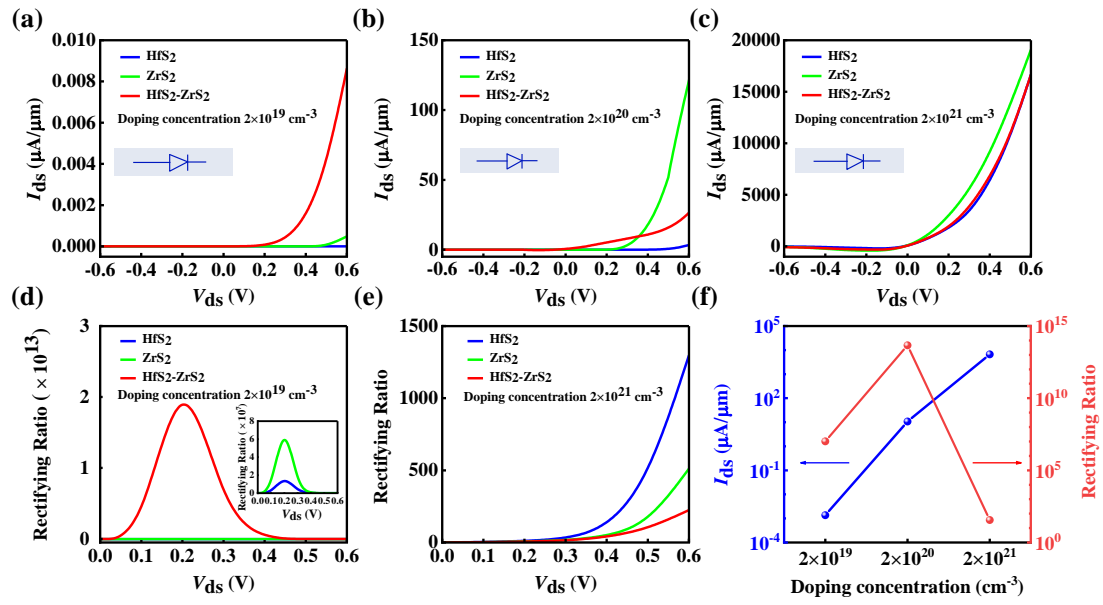


Fig. S3. (a-e) Bias dependent current and rectifying ratio curves of the monolayer diodes with different doping concentrations. (f) The doping concentrations dependent I_{ds} and rectifying ratio curves of the monolayer HfS₂-ZrS₂ lateral diodes.

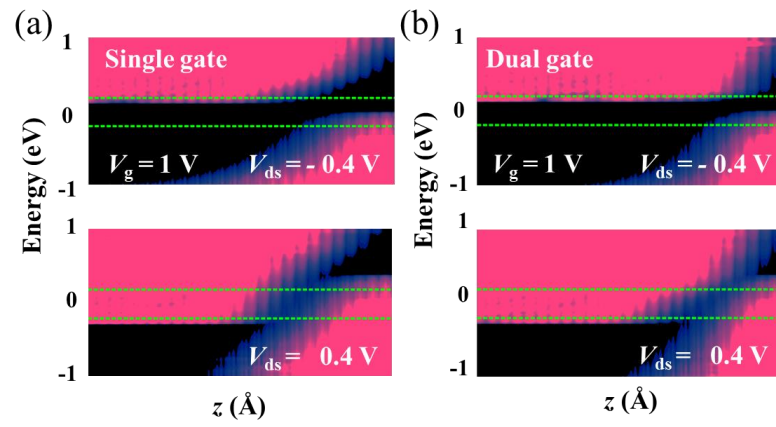


Fig. S4. PDOS of (a) single- and (b) dual-gate under ± 0.4 V bias and 1 V gate voltage.

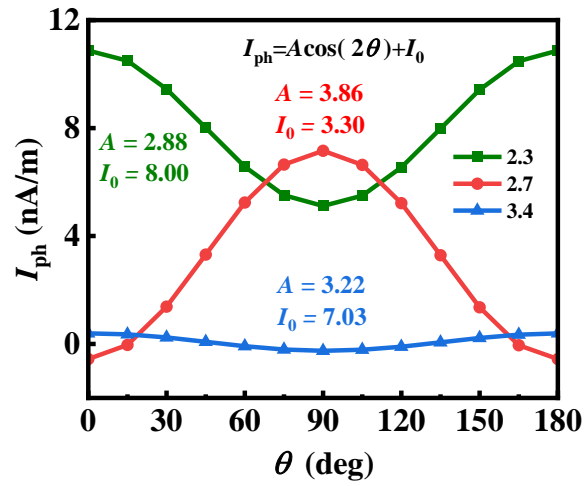


Fig. S5. The photocurrent density of monolayer HfS₂-ZrS₂ lateral heterojunction induced by linearly polarized light respectively at zero bias voltage for photon energies of 2.3, 2.7 and 3.4 eV, respectively.

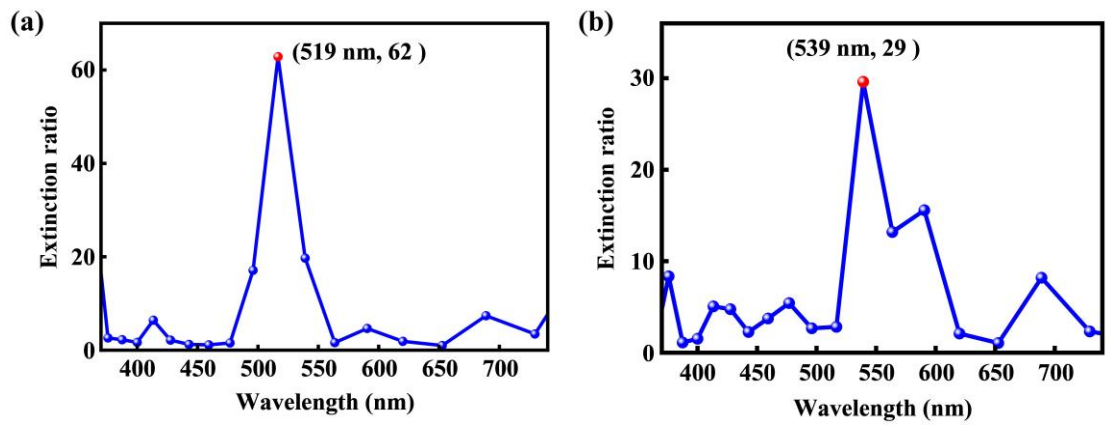


Fig. S6. Extinction ratio of the photocurrent for the monolayer (a)HfS₂- and (b)ZrS₂-based photodetectors.